

N-Channel 150-V (D-S) WFET

PRODUCT SUMMARY			
V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ)
150	0.045 at V _{GS} = 10 V	26	23 nC
	0.047 at V _{GS} = 8 V	25	

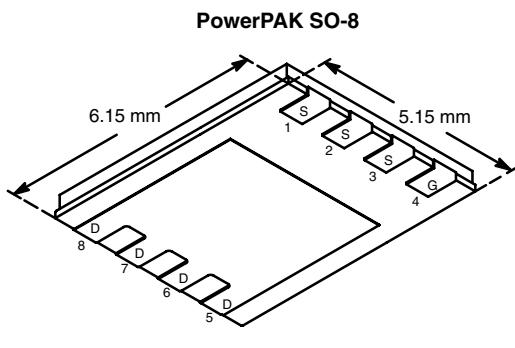
FEATURES

- Extremely Low Q_{gd} WFET[®] Technology for Reduced dV/dt, Q_{gd} and Shoot-Through
- 100 % R_g Tested
- 100 % UIS Tested

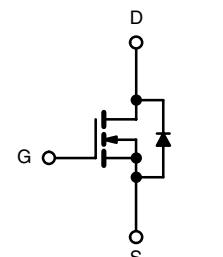

RoHS
COMPLIANT

APPLICATIONS

- Primary Side Switch
- Single-Ended Power Switch



Bottom View
Ordering Information: Si7430DP-T1-E3 (Lead (Pb)-free)



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	150	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150 °C)	I _D	26	A
		21	
		7.2 ^{b, c}	
		5.7 ^{b, c}	
Pulsed Drain Current	I _{DM}	50	W
Continuous Source-Drain Diode Current	I _S	32	
		4.5 ^{b, c}	
Single Pulse Avalanche Current	I _{AS}	20	mJ
Single Pulse Avalanche Energy	E _{AS}	20	
Maximum Power Dissipation	P _D	64	
		44	
		5.2 ^{b, c}	
		3.3 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature) ^{d, e}		260	

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 sec	R _{thJA}	19	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.5	

Notes:

- Based on T_C = 25 °C.
- Surface mounted on 1" x 1" FR4 board.
- t = 10 sec.
- See Solder Profile (<http://www.vishay.com/ppg?73257>). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- Maximum under Steady State conditions is 65 °C/W.

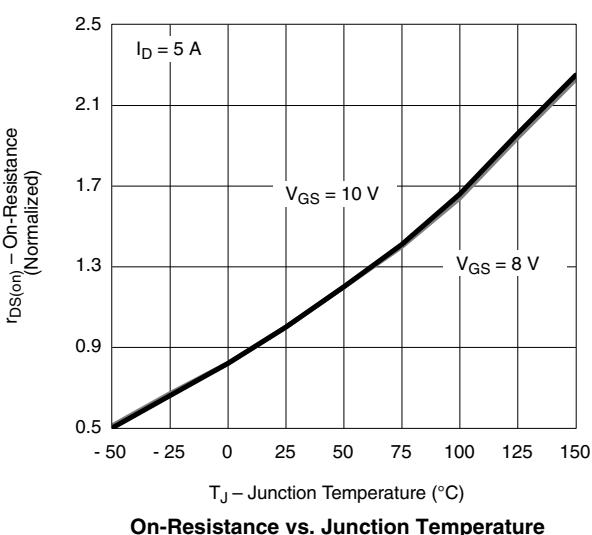
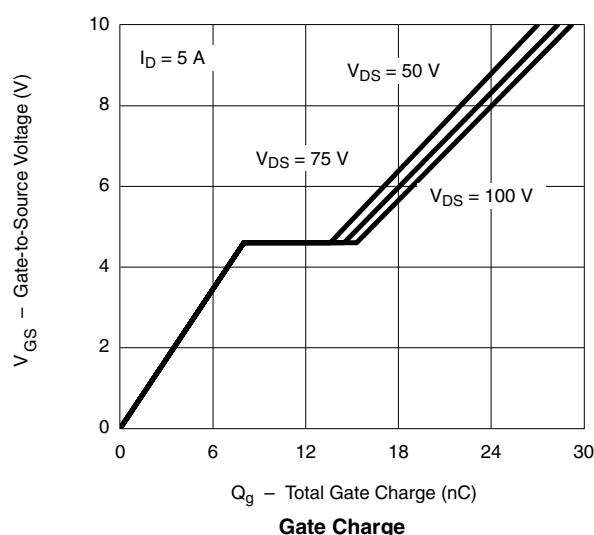
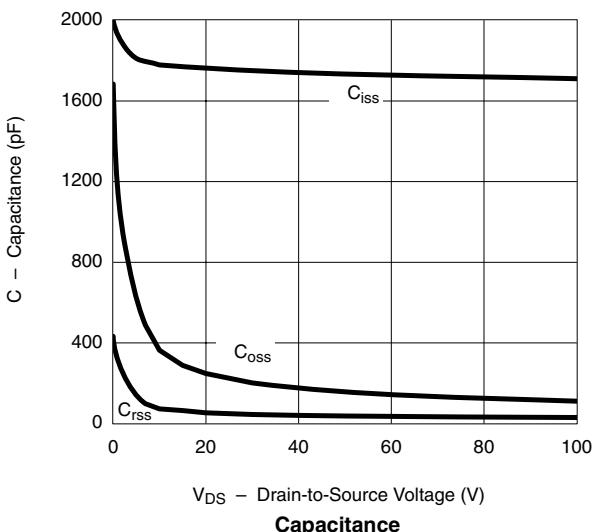
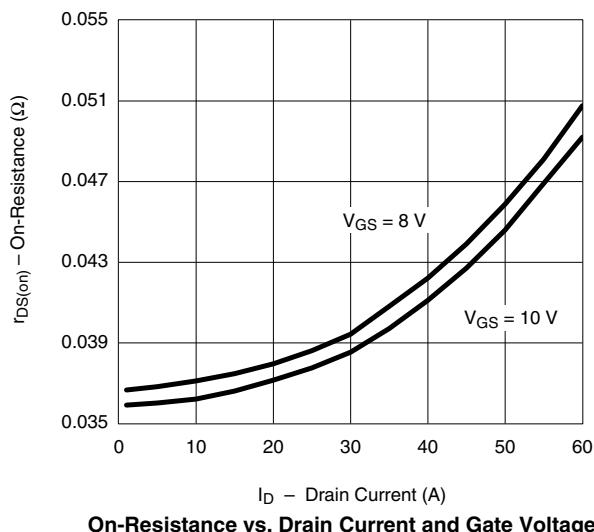
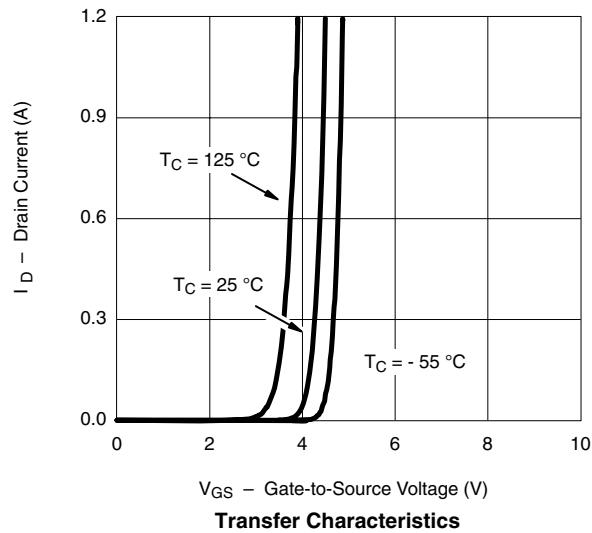
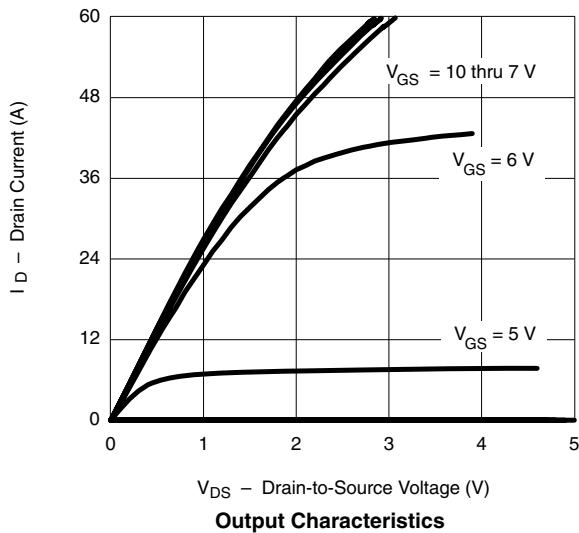
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

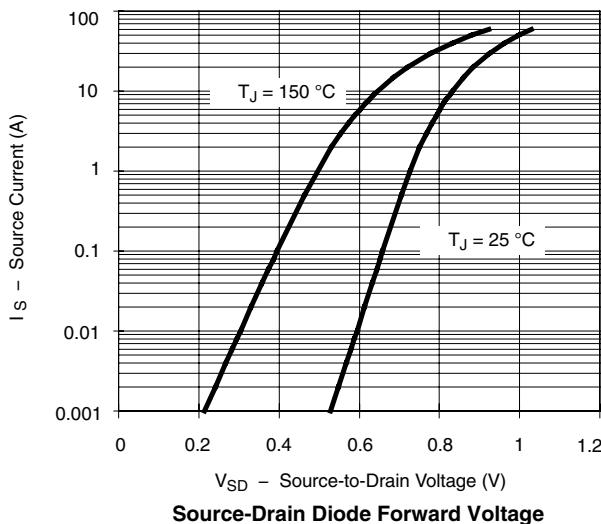
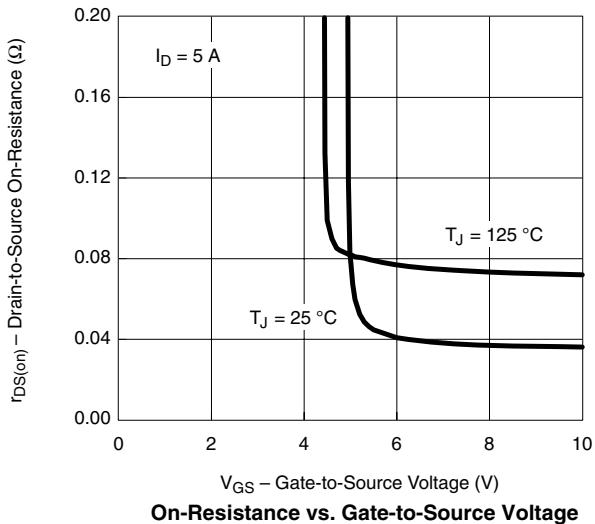
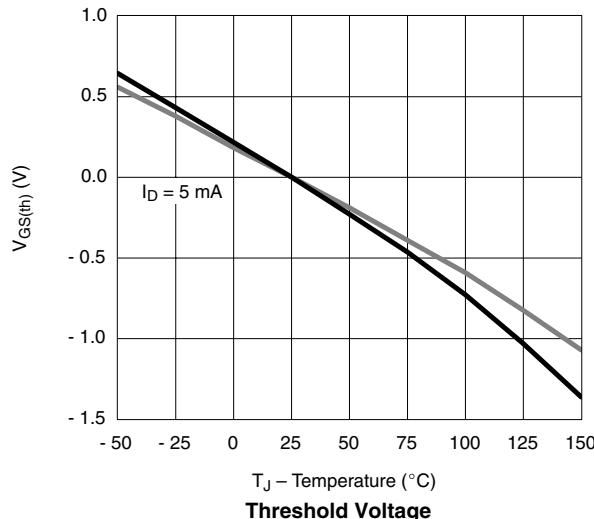
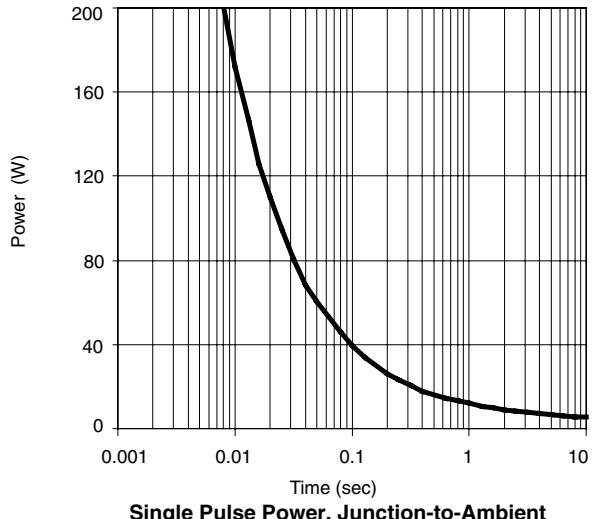
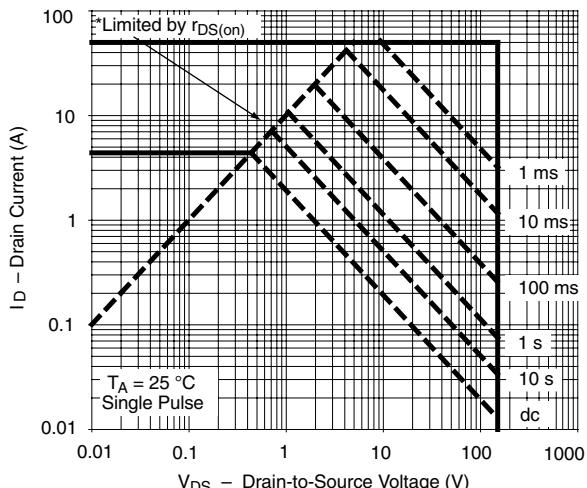
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		172		mV/ $^\circ\text{C}$
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 10		
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.5		4.5	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 150 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 150 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \geq 10 \text{ V}, V_{GS} = 10 \text{ V}$	30			A
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		0.036	0.045	Ω
		$V_{GS} = 8 \text{ V}, I_D = 5 \text{ A}$		0.0375	0.047	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 5 \text{ A}$		23		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1735		pF
Output Capacitance	C_{oss}			160		
Reverse Transfer Capacitance	C_{rss}			37		
Total Gate Charge	Q_g	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		28.5	43	nC
Gate-Source Charge	Q_{gs}			23	35	
Gate-Drain Charge	Q_{gd}			8		
Gate Resistance	R_g		$f = 1 \text{ MHz}$	6.5		
Turn-on Delay Time	$t_{d(\text{on})}$	$V_{DD} = 50 \text{ V}, R_L = 10 \Omega$ $I_D \equiv 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		0.85	1.3	Ω
Rise Time	t_r			14	21	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			12	18	
Fall Time	t_f			22	33	
Turn-On Delay Time	$t_{d(\text{on})}$			6	10	
Rise Time	t_r	$V_{DD} = 50 \text{ V}, R_L = 10 \Omega$ $I_D \equiv 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		16	24	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			12	18	
Fall Time	t_f			20	30	
				7	12	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			32	A
Pulse Diode Forward Current ^a	I_{SM}				50	
Body Diode Voltage	V_{SD}	$I_S = 3 \text{ A}$		0.77	1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 5 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		63	95	ns
Body Diode Reverse Recovery Charge	Q_{rr}			110	165	nC
Reverse Recovery Fall Time	t_a			49		ns
Reverse Recovery Rise Time	t_b			14		

Notes:

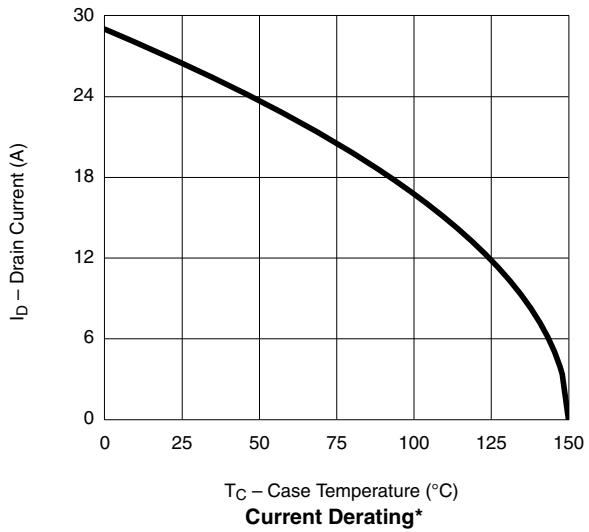
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$
 a. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

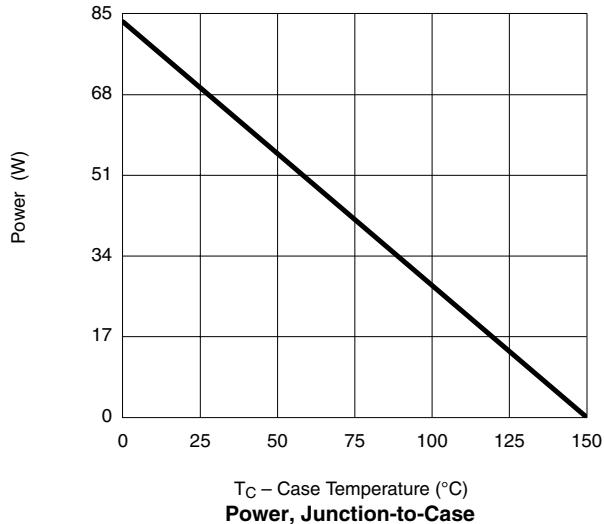
TYPICAL CHARACTERISTICS 25 °C, unless noted


TYPICAL CHARACTERISTICS 25 °C, unless noted**Source-Drain Diode Forward Voltage****On-Resistance vs. Gate-to-Source Voltage****Threshold Voltage****Single Pulse Power, Junction-to-Ambient**

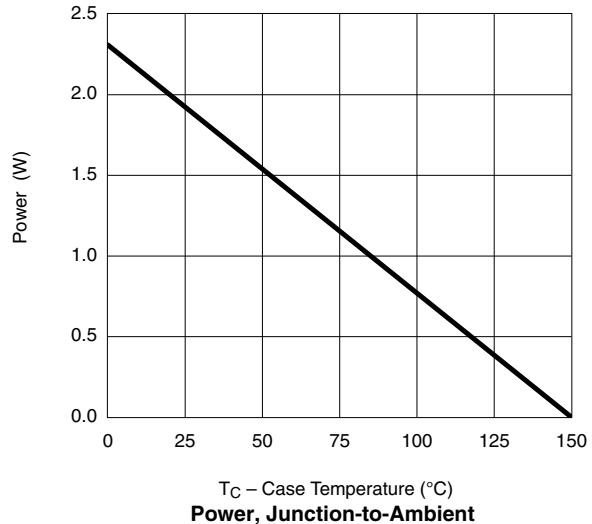
* $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS 25 °C, unless noted


T_C – Case Temperature (°C)
Current Derating*

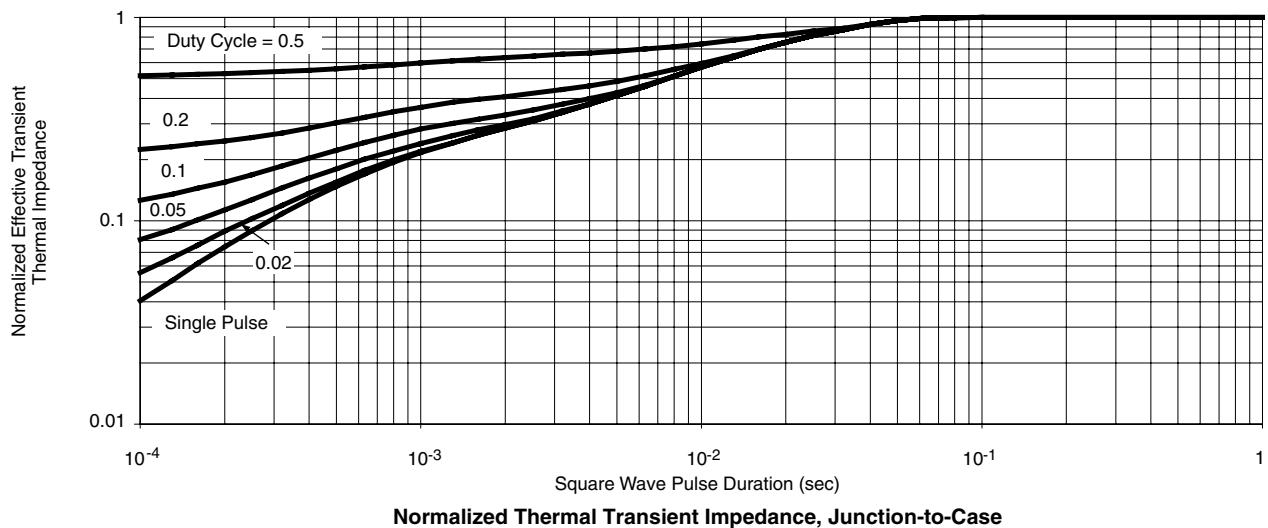
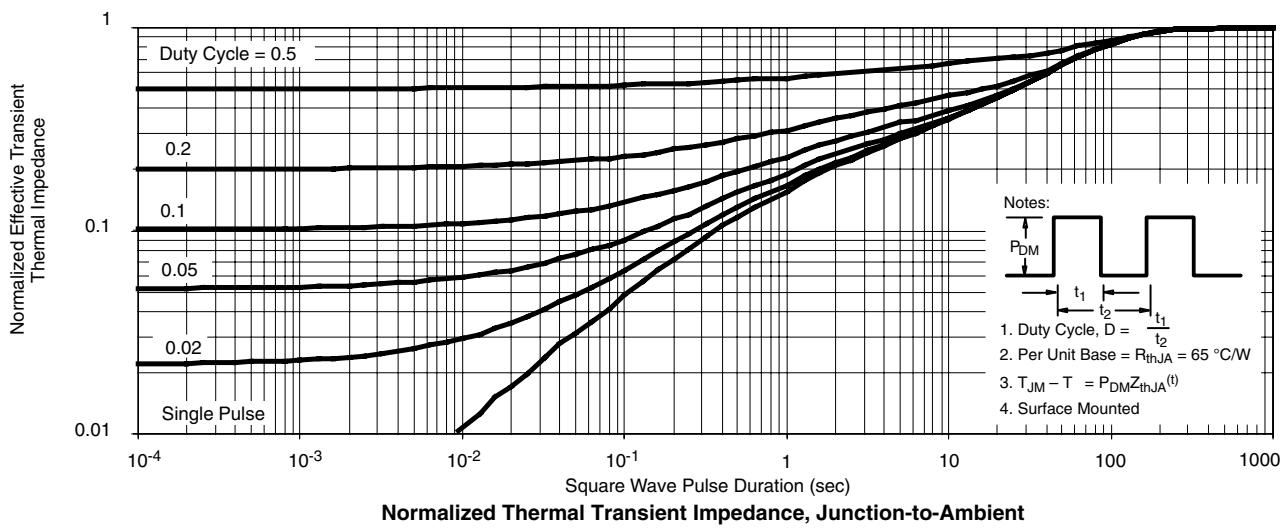


T_C – Case Temperature (°C)
Power, Junction-to-Case



T_C – Case Temperature (°C)
Power, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless noted

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